

Environmentally Benign Deposition of Photoresist and Low-k Dielectrics

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 - Ejection with Single Crystal Silicon
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- Conclusions
- Future Research

Motivation: Waste







• Since a large amount of photoresist, low-*k* and high-*k* dielectrics is wasted during spin coating,

our aim is to **minimize the waste.**

- Develop a fluid ejection system capable of depositing fluids with a minimum of waste.
- Develop a system capable of drop on demand and continuous ejection.
- Develop a coating system to demonstrate waste reduction with full coverage of wafers.
- Demonstrate photoresist and low-k and high-k dielectric coating of 20 cm and 30 cm silicon wafers.

Approach: Full Device







- Use flex-tensional ejectors for deposition
 - Design and implement micro-machined ejector arrays with either single or multiple piezoelectric drivers
- Ejector requirements
 - Able to deposit low and high viscosity fluids
 - No damage caused to the ejected fluids
 - High flow rate
 - Compatible with most chemicals
 - Can be made using IC process technology

Large Scale Single Ejector











Membrane : brass, steel Diameter : 9 mm Membrane thickness : 25 µm Orifice size : 50-200 µm Operating frequencies: 9.5 kHz, 16.4 kHz, 19.0 kHz

- Photoresist covered deep trench
- Deposited PhotoresistThickness :

 $3.5~\mu m \pm 0.15~\mu m$

Direct write with resist:
 350 µm-wide lines

2D Micro-machined Ejector Array





- 2D array of ejectors
- Membrane actuation by a transducer through the fluid reservoir
- Thin single crystal silicon uniform membrane
- Deep reactive ion etched reservoir
- High frequency operation for high flow rate (MHz)
- Drop-on-demand and continuous modes of operation

Fabricated 2D Micro-machined Array: Dimensions





Device Properties

- Membrane material Membrane Diameter Membrane thickness Orifice diameter
- Membrane material : Single crystal silicon, Si₃N₄
- Membrane Diameter : $100 \,\mu\text{m}$, $200 \,\mu\text{m}$, $300 \,\mu\text{m}$, $500 \,\mu\text{m}$, $1 \,\text{mm}$
- Membrane thickness : $1 \,\mu m$ for Si, 2.1 μm for Si₃ N₄
 - : $4 \mu m$, $10 \mu m$, $14 \mu m$
- Operating frequencies: 470 kHz, 1.24 MHz, 2.26 MHz for Si_3N_4

Experimental Setup





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Experimental Setup: Ejecting Device





• Ejection is difficult to see due to very small droplets

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Si_xN_y Membrane (previously fabricated device)





*Two neighboring membranes ejecting at 1.24 MHz simultaneously.*Observed 20 ejecting membranes out of 400.

Ejection Summary	470 KHz	1.24 MHz	2.26 MHz
Droplet Diameter	6.5 um	5 um	3.5 um
Center to Center Distance	14.8 um	14.1 um	9.2 um
Droplet Speed	6.9 m/sec	17.5 m/sec	20.8 m/sec

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- All membranes should be ejecting simultaneously
- Ejection should be perpendicular to the device surface
- Drop on Demand Ejection should be possible
- Droplet size and ejection speed should be controllable

Good Ejection







- Continuous Wave actuation
- All membranes eject simultaneously
- The droplets eject perpendicularly to the device surface

- The aim is to be able eject
 - a desired number of droplets
 - at a desired time

Fabrication Process: SOI Wafer Bonding





DRIE of the Reservoirs





100 μm wide etched holes in silicon wafer.



500 μm wide etched holes in silicon wafer.

Device

5x5 STS etched silicon wafer ready to be bonded to a SOI wafer for membrane formation.

Benefits

- •Uniform 1 μ m thick single crystal silicon membrane.
- •Membrane radius does not depend on the wet oxide etch rate.
- •Uniform membrane radius with Deep Reactive Ion Etching (DRIE).
- •Uniform membrane orifice with dry etching.

Wet SiO₂ Release





• 1 µm thick uniform
 Single Crystal Silicon membranes.

•The ripples on the membranes have disappeared.

• Very clean membrane formation.

Single crystal Si membrane release with wet-etch is completed.

•No polymers are left on the single crystal silicon.







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Old Process vs. New Process: Si₃N₄ vs. Single Crystal Membrane





Silicon-nitride membrane:

The black marks are on the camera tens **not** on the membrane surface.

Single Crystal Si membrane:

Single Crystal Si Membrane Uniformity Check: Ejection at 1.2 MHz







- The yield is normally 100 % on an array.
- A special case is chosen to show uniformity.
- All the 100 µm diameter membranes can eject at
 1.2 MHz indicating the uniformity of the device.
- The other membranes are at the edge of ejection.
- The ones that do not eject at this frequency are bigger size membranes due to bad bonding.



FEM modeling of a Silicon membrane that is 1 μ m thick and 100 μ m in diameter. Membrane and cavity resonance govern operation at resonance for ejection.

	ixesonance inumber								
	0	1	2	3	4				
шц	382 kHz	1.49 MHz	3.34 MHz	5.91 MHz					
200	78 kHz	480 kHz	1.33 MHz	2.72 MHz					
шц	61.26 kHz	238.3 kHz	533.5 kHz	946.9 kHz	1.479 MHz				
500	11.4 kHz	66.4 kHz	187.6 kHz	388.1 kHz	677.1 kHz				
					Vacuum Water				
	500 µm 200 µm	0 382 kHz 00 78 kHz 61.26 kHz 11.4 kHz	0 1 382 kHz 1.49 MHz 00 78 kHz 480 kHz 01 61.26 kHz 238.3 kHz 02 11.4 kHz 66.4 kHz	0 1 2 382 kHz 1.49 MHz 3.34 MHz 78 kHz 480 kHz 1.33 MHz 61.26 kHz 238.3 kHz 533.5 kHz 11.4 kHz 66.4 kHz 187.6 kHz	0 1 2 3 382 kHz 1.49 MHz 3.34 MHz 5.91 MHz 78 kHz 480 kHz 1.33 MHz 2.72 MHz 61.26 kHz 238.3 kHz 533.5 kHz 946.9 kHz 11.4 kHz 66.4 kHz 187.6 kHz 388.1 kHz				

Resonance Number

Recent FEM Work: 100 µm Si Membrane





FEM Work: (A) &(B)





100 µm diameter membrane displacement with and without fluid reservoir.

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FEM Work: (B) Fluid Reservoir Height





100 µm diameter membrane displacement with various fluid reservoir heights.

FEM Work: (C) Transducer @ 3 mm





• Transducer in the far field, good uniformity of displacement of array elements.

• The Standing wave resonance between the device and the transducer

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FEM Work: (C) Transducer @ 500 µm





Transducer in the near field, bad uniformity of displacement of array elements..

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FEM Work: (C) Transducer @ 4 mm



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FEM Work: A Design





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FEM Work: Pressure Amplitude in Reservoirs





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• The membrane displacement is determined by

ANSYS FEM.

- The displacements are applied to the membrane loaded with fluid on one side using COVENTORWARE FEM.
 - Droplet Evolution from the orifice is demonstrated.
 - Droplet size and velocity can be determined.

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FEM Work: Experimental Understanding of the Band Gap

Broadband cMUT Transducer



These experiments are carried on in oil to experimentally search the existence of the band gap predicted by the simulations.

2D Micromachined Acoustic Band Gap Arrays: MABGA in vegetable oil



300 μm membranes diameter and 400 μm periodicity. 50dB Band Gap at 2.9MHz and the reflection coefficient over frequency range.

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2D MABGA in vegetable oil



500 μm membranes diameter and 600 μm periodicity. 23dB Band Gap at 1.3 MHz and the reflection coefficient over frequency range.

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- A new ejector fabrication process has been developed that provides
 - Uniform membranes
 - More control on material properties
 - Stress free membranes (no membrane buckling)
- Demonstrated that all **single crystal silicon** membranes in a 2D Array of micromachined ejectors are uniform and capable of ejection at 1.2 MHz.



- Finite Element Simulations are demonstrated.
 - Operate at the far field.
 - The fluid reservoir height should be designed for broad band operation.
 - Membrane, cavity, standing wave resonance's should match for ejection.
- Demonstrated the first 2D Micromachined Acoustic Band Gap Array spectral response.



- Perform further FEM simulations to understand crosstalk issues and model the devices.
- Utilize the understanding of device operation to improve the design of 2D Micromachined Ejector Arrays .
- Using the new fabrication process to build ejectors capable of better controlled ejection
 - Drop on Demand ejection
 - All array membranes active at a given time
- Demonstrate full photoresist coverage of a wafer using micro-machined 2D ejector arrays.